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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-fvq100

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Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	–	–	–	–	Yes	Yes
Boundary Scan Test (BST)	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–

3.3.7 Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200 μ s to allow for charge pumps to power up, and device initialization will begin.

3.4 Power Dissipation

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation.

3.4.1 General Power Equation

$$P = [ICC_{\text{standby}} + ICC_{\text{active}}] * V_{CC1} + I_{OL} * V_{OL} * N + I_{OH} * (V_{CC1} - V_{OH}) * M$$

EQ 1

where:

- ICC_{standby} is the current flowing when no inputs or outputs are changing.
- ICC_{active} is the current flowing due to CMOS switching.
- I_{OL} , I_{OH} are TTL sink/source currents.
- V_{OL} , V_{OH} are TTL level output voltages.
- N equals the number of outputs driving TTL loads to V_{OL} .
- M equals the number of outputs driving TTL loads to V_{OH} .

Accurate values for N and M are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

3.4.2 Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

3.4.3 Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

The power dissipated by a CMOS circuit can be expressed by the equation:

$$\text{Power}(\mu\text{W}) = C_{EQ} * V_{CCA2}^2 * F(1)$$

EQ 2

where:

- C_{EQ} = Equivalent capacitance expressed in picofarads (pF)

Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Microsemi's integrated verification and logic analysis tool. Another tool included in the Libero software is the SmartGen macro builder, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design.

Microsemi's Libero software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synopsys, and Cadence design systems.

See the Libero IDE web content at www.microsemi.com/soc/products/software/libero/default.aspx for further information on licensing and current operating system support.

3.6 Related Documents

The following sections give the list of related documents which can be referred for this datasheet.

3.6.1 Application Notes

- AC278: *BSDL Files Format Description*
- AC225: *Programming Antifuse Devices*
- AC168: *Implementation of Security in Microsemi Antifuse FPGAs*

3.6.2 User Guides and Manuals

- *Antifuse Macro Library Guide*
- *Silicon Sculptor Programmers User Guide*

3.6.3 Miscellaneous

Libero IDE Flow Diagram

3.7 5.0 V Operating Conditions

The following tables show 5.0 V operating conditions.

Table 12 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCC+0.5	V
VO	Output Voltage	-0.5 to VCC+0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 13 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCI+0.5	V
VO	Output Voltage	-0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

3.8.1 3.3 V LVTTL Electrical Specifications

Table 19 • 3.3V LVTTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = -4 mA	2.15		2.15		2.4		2.4		V
VOL ¹	IOL = 6 mA		0.4		0.4		0.48		0.48	V
VIL		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL			-10		-10		-10		-10	µA
IIH			-10		-10		-10		-10	µA
Input Transition Time, T _R and T _F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ²	A40MX02, A40MX04	3		25		10		25		mA
	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	15		25		25		25		mA
Low-Power Mode Standby Current	42MX devices only	0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0		mA
IIO, I/O source sink current	Can be derived from the <i>IB/S model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min.
2. All outputs unloaded. All inputs = VCC/VCCI or GND.

3.9 Mixed 5.0 V / 3.3 V Operating Conditions (for 42MX Devices Only)

Table 20 • Absolute Maximum Ratings*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCA + 0.5	V
VO	Output Voltage	-0.5 to VCCI + 0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device

reliability. Devices should not be operated outside the recommended operating conditions.

Table 21 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	-40 to +85	-55 to +125	°C
VCCA	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI	3.14 to 3.47	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

approximately a 3 ns to a 6 ns delay, which is represented statistically in higher fanout (FO=8) routing delays in the data sheet specifications section, shown in Table 34, page 41.

3.11.3 Timing Derating

MX devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature and worst-case processing.

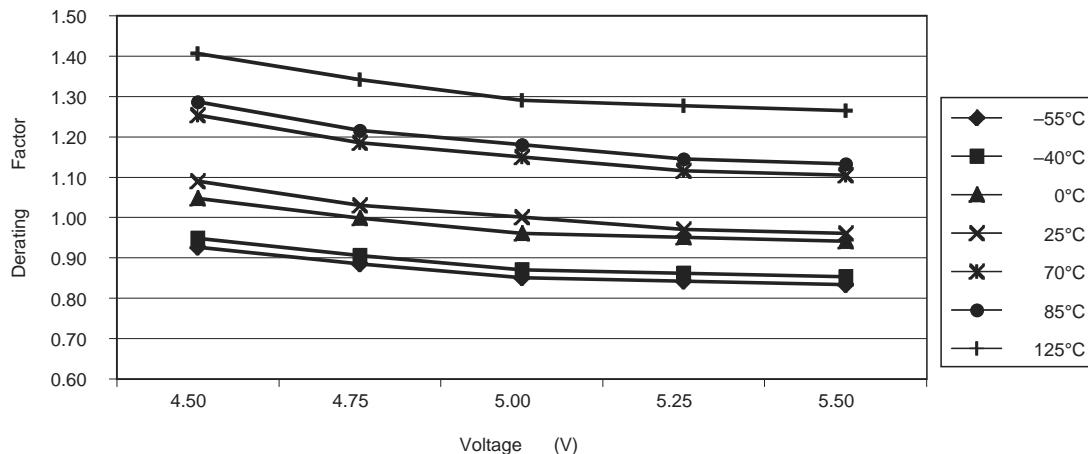
3.11.4 Temperature and Voltage Derating Factors

The following tables and figures show temperature and voltage derating factors for 40MX and 42MX FPGAs.

Table 28 • 42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $VCCA = 5.0 \text{ V}$)

Temperature								
42MX Voltage	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C	
4.50	0.93	0.95	1.05	1.09	1.25	1.29	1.41	
4.75	0.88	0.90	1.00	1.03	1.18	1.22	1.34	
5.00	0.85	0.87	0.96	1.00	1.15	1.18	1.29	
5.25	0.84	0.86	0.95	0.97	1.12	1.14	1.28	
5.50	0.83	0.85	0.94	0.96	1.10	1.13	1.26	

Figure 34 • 42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $VCCA = 5.0 \text{ V}$)



Note: This derating factor applies to all routing and propagation delays

Table 29 • 40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $VCC = 5.0 \text{ V}$)

Temperature								
40MX Voltage	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C	
4.50	0.89	0.93	1.02	1.09	1.25	1.31	1.45	
4.75	0.84	0.88	0.97	1.03	1.18	1.24	1.37	
5.00	0.82	0.85	0.94	1.00	1.15	1.20	1.33	
5.25	0.80	0.82	0.91	0.97	1.12	1.16	1.29	
5.50	0.79	0.82	0.90	0.96	1.10	1.15	1.28	

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays											
t _{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5 ns
t _{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3 ns
Input Module Predicted Routing Delays¹											
t _{IRD1}	FO = 1 Routing Delay		2.1		2.4		2.2		3.2		4.5 ns
t _{IRD2}	FO = 2 Routing Delay		2.6		3.0		3.4		4.0		5.6 ns
t _{IRD3}	FO = 3 Routing Delay		3.1		3.6		4.1		4.8		6.7 ns
t _{IRD4}	FO = 4 Routing Delay		3.6		4.2		4.8		5.6		7.8 ns
t _{IRD8}	FO = 8 Routing Delay		5.7		6.6		7.5		8.8		12.4 ns
Global Clock Network											
t _{CKH}	Input Low to HIGH	FO = 16	4.6		5.3		6.0		7.0		9.8 ns
		FO = 128	4.6		5.3		6.0		7.0		9.8
t _{CKL}	Input High to LOW	FO = 16	4.8		5.6		6.3		7.4		10.4 ns
		FO = 128	4.8		5.6		6.3		7.4		10.4
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.1		3.6		5.1
t _{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.01		3.6		5.1
t _{CKSW}	Maximum Skew	FO = 16	0.4		0.5		0.5		0.6		0.8 ns
		FO = 128	0.5		0.6		0.7		0.8		1.2
t _P	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.0 ns
		FO = 128	4.8		5.6		6.3		7.5		10.4
f _{MAX}	Maximum Frequency	FO = 16	188		175		160		139		83 MHz
		FO = 128	181		168		154		134		80

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing¹											
t _{DH}	Data-to-Pad HIGH		3.9		4.5		5.1		6.05		8.5 ns
t _{DHL}	Data-to-Pad LOW		3.4		3.9		4.4		5.2		7.3 ns
t _{ENZH}	Enable Pad Z to HIGH		3.4		3.9		4.4		5.2		7.3 ns
t _{ENZL}	Enable Pad Z to LOW		4.9		5.6		6.4		7.5		10.5 ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.0 ns
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6 ns
d _{TLH}	Delta LOW to HIGH		0.03		0.04		0.04		0.05		0.07 ns/pF
d _{THL}	Delta HIGH to LOW		0.02		0.02		0.03		0.03		0.04 ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer utility from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCC = 3.0 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays											
t _{PD1}	Single Module		1.7		2.0		2.3		2.7		3.7 ns
t _{PD2}	Dual-Module Macros		3.7		4.3		4.9		5.7		8.0 ns
t _{CO}	Sequential Clock-to-Q		1.7		2.0		2.3		2.7		3.7 ns
t _{GO}	Latch G-to-Q		1.7		2.0		2.3		2.7		3.7 ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.7		2.0		2.3		2.7		3.7 ns
Logic Module Predicted Routing Delays¹											
t _{RD1}	FO = 1 Routing Delay		1.9		2.2		2.5		3.0		4.2 ns
t _{RD2}	FO = 2 Routing Delay		2.7		3.1		3.5		4.1		5.7 ns
t _{RD3}	FO = 3 Routing Delay		3.4		3.9		4.4		5.2		7.3 ns
t _{RD4}	FO = 4 Routing Delay		4.1		4.8		5.4		6.3		8.9 ns
t _{RD8}	FO = 8 Routing Delay		7.1		8.1		9.2		10.9		15.2 ns
Logic Module Sequential Timing²											
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		4.3		5.0		5.6		6.6		9.2 ns
t _{HD} ³	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0	
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	4.3		5.0		5.6		6.6		9.2	
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0	

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, V_{CC} = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays¹											
t _{IRD1}	FO = 1 Routing Delay		2.9		3.3		3.8		4.5		6.3 ns
t _{IRD2}	FO = 2 Routing Delay		3.6		4.2		4.8		5.6		7.8 ns
t _{IRD3}	FO = 3 Routing Delay		4.4		5.0		5.7		6.7		9.4 ns
t _{IRD4}	FO = 4 Routing Delay		5.1		5.9		6.7		7.8		11.0 ns
t _{IRD8}	FO = 8 Routing Delay		8.0		9.3		10.5		12.4		17.2 ns
Global Clock Network											
t _{CKH}	Input LOW to HIGH	FO = 16	6.4		7.4		8.4		9.9		13.8 ns
		FO = 128	6.4		7.4		8.4		9.9		13.8
t _{CKL}	Input HIGH to LOW	FO = 16	6.8		7.8		8.9		10.4		14.6 ns
		FO = 128	6.8		7.8		8.9		10.4		14.6
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	3.1		3.6		4.1		4.8		6.7 ns
		FO = 128	3.3		3.8		4.3		5.1		7.1
t _{PWL}	Minimum Pulse Width LOW	FO = 16	3.1		3.6		4.1		4.8		6.7 ns
		FO = 128	3.3		3.8		4.3		5.1		7.1
t _{CKSW}	Maximum Skew	FO = 16	0.6		0.6		0.7		0.8		1.2 ns
		FO = 128	0.8		0.9		1.0		1.2		1.6
t _P	Minimum Period	FO = 16	6.5		7.5		8.5		10.1		14.1 ns
		FO = 128	6.8		7.8		8.9		10.4		14.6
f _{MAX}	Maximum Frequency	FO = 16	113		105		96		83		50 MHz
		FO = 128	109		101		92		80		48
TTL Output Module Timing⁴											
t _{D LH}	Data-to-Pad HIGH		4.7		5.4		6.1		7.2		10.0 ns
t _{D HL}	Data-to-Pad LOW		5.6		6.4		7.3		8.6		12.0 ns
t _{ENZH}	Enable Pad Z to HIGH		5.2		6.0		6.9		8.1		11.3 ns
t _{ENZL}	Enable Pad Z to LOW		6.6		7.6		8.6		10.1		14.1 ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9 ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7 ns
d _{TLH}	Delta LOW to HIGH		0.03		0.03		0.04		0.04		0.06 ns/pF
d _{THL}	Delta HIGH to LOW		0.04		0.04		0.05		0.06		0.08 ns/pF

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		4.9		5.6		6.6		9.2		ns
t _A	Flip-Flop Clock Input Period	3.5		3.8		4.3		5.1		7.1		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency	268		244		224		195		117		MHz

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing⁵											
t _{DH}	Data-to-Pad HIGH	2.5	2.7	3.1	3.6	5.1	ns				
t _{DHL}	Data-to-Pad LOW	2.9	3.2	3.6	4.3	6.0	ns				
t _{ENZH}	Enable Pad Z to HIGH	2.6	2.9	3.3	3.9	5.5	ns				
t _{ENZL}	Enable Pad Z to LOW	2.9	3.2	3.7	4.3	6.1	ns				
t _{ENHZ}	Enable Pad HIGH to Z	4.9	5.4	6.2	7.3	10.2	ns				
t _{ENLZ}	Enable Pad LOW to Z	5.3	5.9	6.7	7.9	11.1	ns				
t _{GLH}	G-to-Pad HIGH	2.6	2.9	3.3	3.8	5.3	ns				
t _{GHL}	G-to-Pad LOW	2.6	2.9	3.3	3.8	5.3	ns				
t _{LSU}	I/O Latch Set-Up	0.5	0.5	0.6	0.7	1.0	ns				
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns				
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	5.2	5.8	6.6	7.7	10.8	ns				
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	7.4	8.2	9.3	10.9	15.3	ns				
d _{TLH}	Capacity Loading, LOW to HIGH	0.03	0.03	0.03	0.04	0.06	ns/pF				
d _{THL}	Capacity Loading, HIGH to LOW	0.04	0.04	0.04	0.05	0.07	ns/pF				

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing⁵											
t _{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1 ns
t _{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0 ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		2.9		3.3		3.9		5.5 ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1 ns
t _{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2 ns
t _{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1 ns
t _{GLH}	G-to-Pad HIGH		4.2		4.6		5.2		6.1		8.6 ns
t _{GHL}	G-to-Pad LOW		4.2		4.6		5.2		6.1		8.6 ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0	ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8 ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3 ns
d _{TLH}	Capacity Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07	ns/pF

- For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
- Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
- Delays based on 35 pF loading

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays¹											
t _{PD1}	Single Module	1.6		1.8		2.1		2.5		3.5	ns
t _{CO}	Sequential Clock-to-Q	1.8		2.0		2.3		2.7		3.8	ns
t _{GO}	Latch G-to-Q	1.7		1.9		2.1		2.5		3.5	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q	2.0		2.2		2.5		2.9		4.1	ns
Logic Module Predicted Routing Delays²											
t _{RD1}	FO = 1 Routing Delay	1.0		1.1		1.2		1.4		2.0	ns
t _{RD2}	FO = 2 Routing Delay	1.3		1.4		1.6		1.9		2.7	ns
t _{RD3}	FO = 3 Routing Delay	1.6		1.8		2.0		2.4		3.3	ns

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD4}	FO = 4 Routing Delay			1.9		2.1		2.4		2.9		4.0 ns
t _{RD8}	FO = 8 Routing Delay			3.2		3.6		4.1		4.8		6.7 ns
Logic Module Sequential Timing^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.5		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.7		5.3		6.0		7.0		9.8	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.8		9.2		12.9	ns
t _A	Flip-Flop Clock Input Period	5.0		5.6		6.2		7.1		9.9		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{NSU}	Input Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		161		146		135		117		70	MHz

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PWL} Minimum Pulse Width LOW	FO = 32	5.3	5.9	6.7	7.8	11.0	ns				
	FO = 384	6.2	6.9	7.9	9.2	12.9	ns				
t _{CKSW} Maximum Skew	FO = 32		0.5	0.5	0.6	0.7	1.0	ns			
	FO = 384		2.2	2.4	2.7	3.2	4.5	ns			
t _{SUEXT} Input Latch External Set-Up	FO = 32	0.0	0.0	0.0	0.0	0.0	0.0	ns			
	FO = 384	0.0	0.0	0.0	0.0	0.0	0.0	ns			
t _{HEXT} Input Latch External Hold	FO = 32	3.9	4.3	4.9	5.7	8.0	ns				
	FO = 384	4.5	4.9	5.6	6.6	9.2	ns				
t _P Minimum Period	FO = 32	7.0	7.8	8.4	9.7	16.2	ns				
	FO = 384	7.7	8.6	9.3	10.7	17.8	ns				
f _{MAX} Maximum Frequency	FO = 32		142	129	119	103	62	MHz			
	FO = 384		129	117	108	94	56	MHz			
TTL Output Module Timing⁵											
t _{DLH} Data-to-Pad HIGH			3.5	3.9	4.4	5.2	7.3	ns			
t _{DHL} Data-to-Pad LOW			4.1	4.6	5.2	6.1	8.6	ns			
t _{ENZH} Enable Pad Z to HIGH			3.8	4.2	4.8	5.6	7.8	ns			
t _{ENZL} Enable Pad Z to LOW			4.2	4.6	5.3	6.2	8.7	ns			
t _{ENHZ} Enable Pad HIGH to Z			7.6	8.4	9.5	11.2	15.7	ns			
t _{ENLZ} Enable Pad LOW to Z			7.0	7.8	8.8	10.4	14.5	ns			
t _{GLH} G-to-Pad HIGH			4.8	5.3	6.0	7.2	10.0	ns			
t _{GHL} G-to-Pad LOW			4.8	5.3	6.0	7.2	10.0	ns			
t _{LCO} I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading			8.0	8.9	10.1	11.9	16.7	ns			
t _{ACO} Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading			11.3	12.5	14.2	16.7	23.3	ns			
d _{TLH} Capacitive Loading, LOW to HIGH			0.04	0.04	0.05	0.06	0.08	ns/pF			
d _{THL} Capacitive Loading, HIGH to LOW			0.05	0.05	0.06	0.07	0.10	ns/pF			
CMOS Output Module Timing⁵											
t _{DLH} Data-to-Pad HIGH			4.5	5.0	5.6	6.6	9.3	ns			
t _{DHL} Data-to-Pad LOW			3.4	3.8	4.3	5.1	7.1	ns			
t _{ENZH} Enable Pad Z to HIGH			3.8	4.2	4.8	5.6	7.8	ns			
t _{ENZL} Enable Pad Z to LOW			4.2	4.6	5.3	6.2	8.7	ns			
t _{ENHZ} Enable Pad HIGH to Z			7.6	8.4	9.5	11.2	15.7	ns			
t _{ENLZ} Enable Pad LOW to Z			7.0	7.8	8.8	10.4	14.5	ns			
t _{GLH} G-to-Pad HIGH			7.1	7.9	8.9	10.5	14.7	ns			
t _{GHL} G-to-Pad LOW			7.1	7.9	8.9	10.5	14.7	ns			
t _{LCO} I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading			8.0	8.9	10.1	11.9	16.7	ns			

Table 49 • PL84

PL84	Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	I/O		DCLK, I/O	DCLK, I/O	DCLK, I/O
11	I/O		I/O	I/O	I/O
12	NC		MODE	MODE	MODE
13	I/O		I/O	I/O	I/O
14	I/O		I/O	I/O	I/O
15	I/O		I/O	I/O	I/O
16	I/O		I/O	I/O	I/O
17	I/O		I/O	I/O	I/O
18	GND		I/O	I/O	I/O
19	GND		I/O	I/O	I/O
20	I/O		I/O	I/O	I/O
21	I/O		I/O	I/O	I/O
22	I/O		VCCA	VCCI	VCCI
23	I/O		VCCI	VCCA	VCCA
24	I/O		I/O	I/O	I/O
25	VCC		I/O	I/O	I/O
26	VCC		I/O	I/O	I/O
27	I/O		I/O	I/O	I/O
28	I/O		GND	GND	GND
29	I/O		I/O	I/O	I/O
30	I/O		I/O	I/O	I/O
31	I/O		I/O	I/O	I/O
32	I/O		I/O	I/O	I/O
33	VCC		I/O	I/O	I/O
34	I/O		I/O	I/O	TMS, I/O
35	I/O		I/O	I/O	TDI, I/O
36	I/O		I/O	I/O	WD, I/O
37	I/O		I/O	I/O	I/O
38	I/O		I/O	I/O	WD, I/O
39	I/O		I/O	I/O	WD, I/O
40	GND		I/O	I/O	I/O
41	I/O		I/O	I/O	I/O
42	I/O		I/O	I/O	I/O
43	I/O		VCCA	VCCA	VCCA
44	I/O		I/O	I/O	WD, I/O
45	I/O		I/O	I/O	WD, I/O
46	VCC		I/O	I/O	WD, I/O

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Table 53 • PQ208

PQ208	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
	169	I/O	WD, I/O	WD, I/O
	170	I/O	I/O	I/O
	171	NC	I/O	QCLKD, I/O
	172	I/O	I/O	I/O
	173	I/O	I/O	I/O
	174	I/O	I/O	I/O
	175	I/O	I/O	I/O
	176	I/O	WD, I/O	WD, I/O
	177	I/O	WD, I/O	WD, I/O
	178	PRA, I/O	PRA, I/O	PRA, I/O
	179	I/O	I/O	I/O
	180	CLKA, I/O	CLKA, I/O	CLKA, I/O
	181	NC	I/O	I/O
	182	NC	VCCI	VCCI
	183	VCCA	VCCA	VCCA
	184	GND	GND	GND
	185	I/O	I/O	I/O
	186	CLKB, I/O	CLKB, I/O	CLKB, I/O
	187	I/O	I/O	I/O
	188	PRB, I/O	PRB, I/O	PRB, I/O
	189	I/O	I/O	I/O
	190	I/O	WD, I/O	WD, I/O
	191	I/O	WD, I/O	WD, I/O
	192	I/O	I/O	I/O
	193	NC	I/O	I/O
	194	NC	WD, I/O	WD, I/O
	195	NC	WD, I/O	WD, I/O
	196	I/O	I/O	QCLKC, I/O
	197	NC	I/O	I/O
	198	I/O	I/O	I/O
	199	I/O	I/O	I/O
	200	I/O	I/O	I/O
	201	NC	I/O	I/O
	202	VCCI	VCCI	VCCI
	203	I/O	WD, I/O	WD, I/O
	204	I/O	WD, I/O	WD, I/O
	205	I/O	I/O	I/O

Table 57 • TQ176

TQ176	Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
	47	I/O	I/O	TDI, I/O
	48	I/O	I/O	I/O
	49	I/O	I/O	WD, I/O
	50	I/O	I/O	WD, I/O
	51	I/O	I/O	I/O
	52	NC	VCCI	VCCI
	53	I/O	I/O	I/O
	54	NC	I/O	I/O
	55	NC	I/O	WD, I/O
	56	I/O	I/O	WD, I/O
	57	NC	NC	I/O
	58	I/O	I/O	I/O
	59	I/O	I/O	WD, I/O
	60	I/O	I/O	WD, I/O
	61	NC	I/O	I/O
	62	I/O	I/O	I/O
	63	I/O	I/O	I/O
	64	NC	I/O	I/O
	65	I/O	I/O	I/O
	66	NC	I/O	I/O
	67	GND	GND	GND
	68	VCCA	VCCA	VCCA
	69	I/O	I/O	WD, I/O
	70	I/O	I/O	WD, I/O
	71	I/O	I/O	I/O
	72	I/O	I/O	I/O
	73	I/O	I/O	I/O
	74	NC	I/O	I/O
	75	I/O	I/O	I/O
	76	I/O	I/O	I/O
	77	NC	NC	WD, I/O
	78	NC	I/O	WD, I/O
	79	I/O	I/O	I/O
	80	NC	I/O	I/O
	81	I/O	I/O	I/O
	82	NC	VCCI	VCCI
	83	I/O	I/O	I/O

Table 62 • CQ172

21	I/O
22	GND
23	VCCI
24	VSV
25	I/O
26	I/O
27	VCC
28	I/O
29	I/O
30	I/O
31	I/O
32	GND
33	I/O
34	I/O
35	I/O
36	I/O
37	GND
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	BININ
45	BINOUT
46	I/O
47	I/O
48	I/O
49	I/O
50	VCCI
51	I/O
52	I/O
53	I/O
54	I/O
55	GND
56	I/O
57	I/O
58	I/O
59	I/O